

**Metrological station "COSMOS". Current status.**





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# "COSMOS" beamline : The main tasks

Development of procedures and carrying out of absolute calibration in the soft X-ray and VUV (10-2000 eV) for:

- any kinds of X-ray optics (grates, mirrors etc.)
- ready-fitted appliance (spectrometers, radiometers, telescopes)
- detectors (in particular absolute spectral responsivity )



# Application fields

- Astrophysical observations at the soft X-ray range
- Diagnostic of high-temperature plasma
- Equipment for the EUV-lithography ( $\lambda=13$  nm)

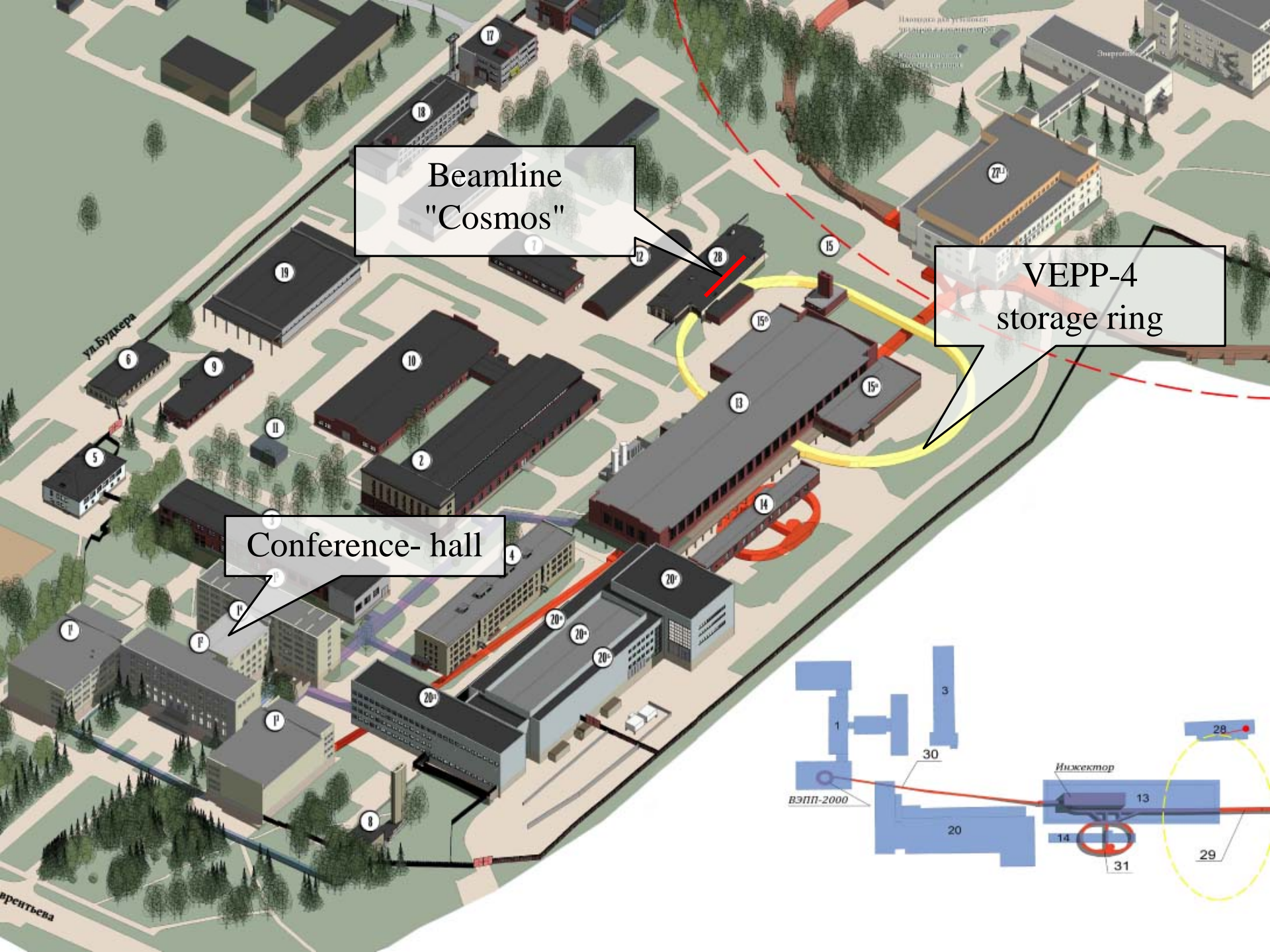


## **SR station "Space"**

*Metrology at the soft X-ray and VUV ranges*

- *High-vacuum windowless beamline*
- *Source - bending magnet VEPP-4 storage ring*
- *Spectral range - 10-2000 eV*
- *First light - 2007*

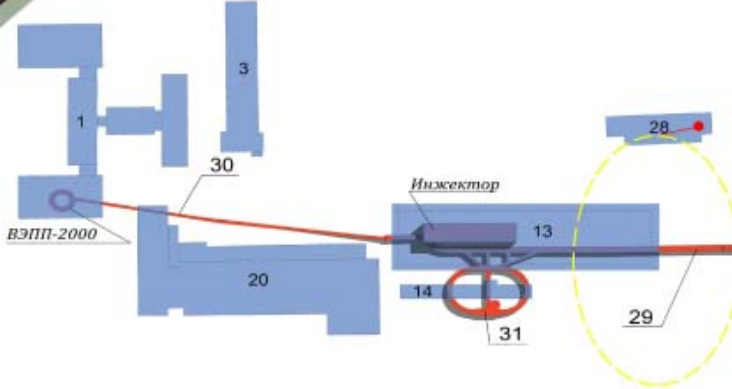




Beamline  
"Cosmos"

VEPP-4  
storage ring

Conference- hall





# "Cosmos" Beamline at the VEPP-4 SR experimental hall

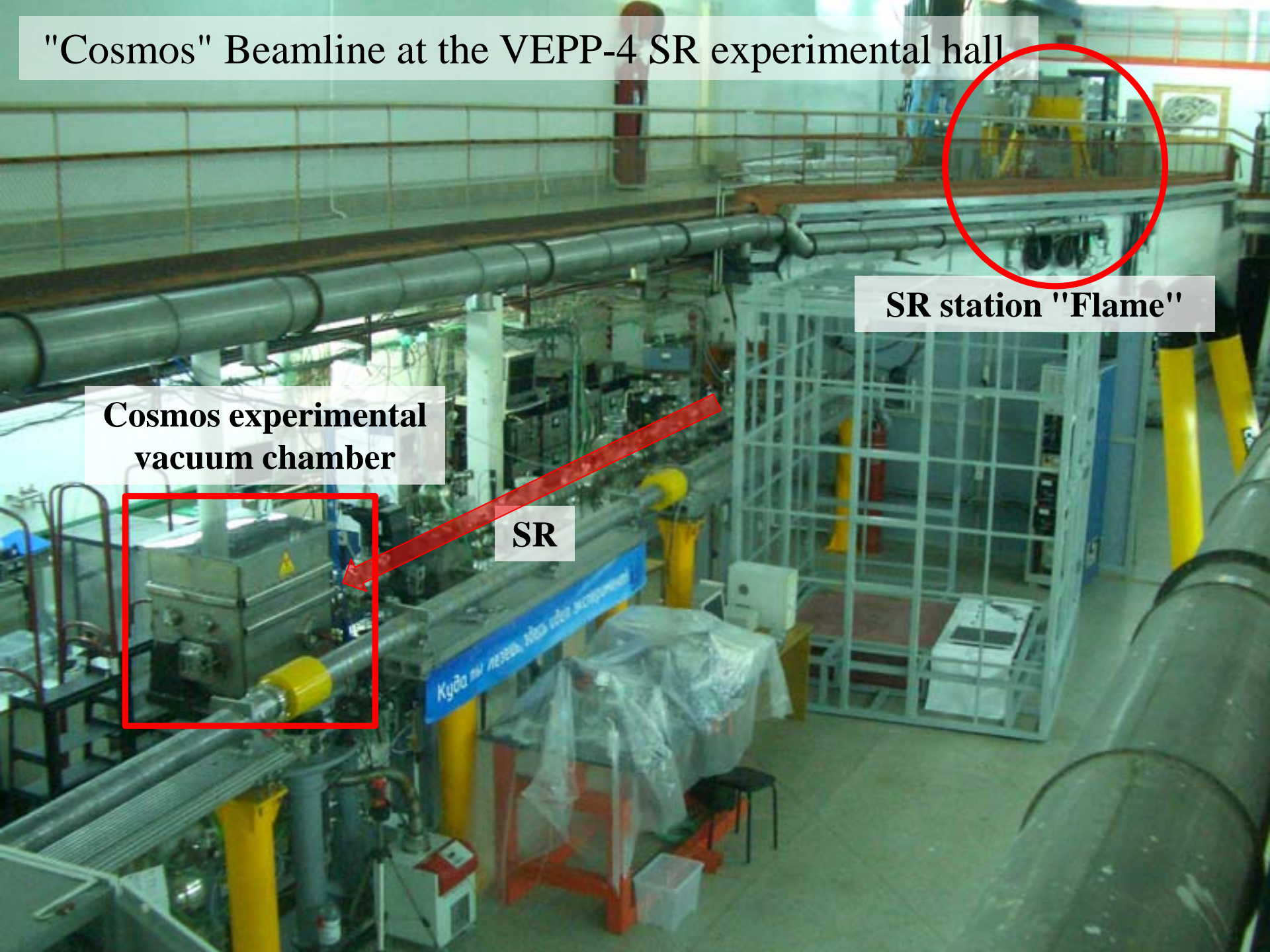


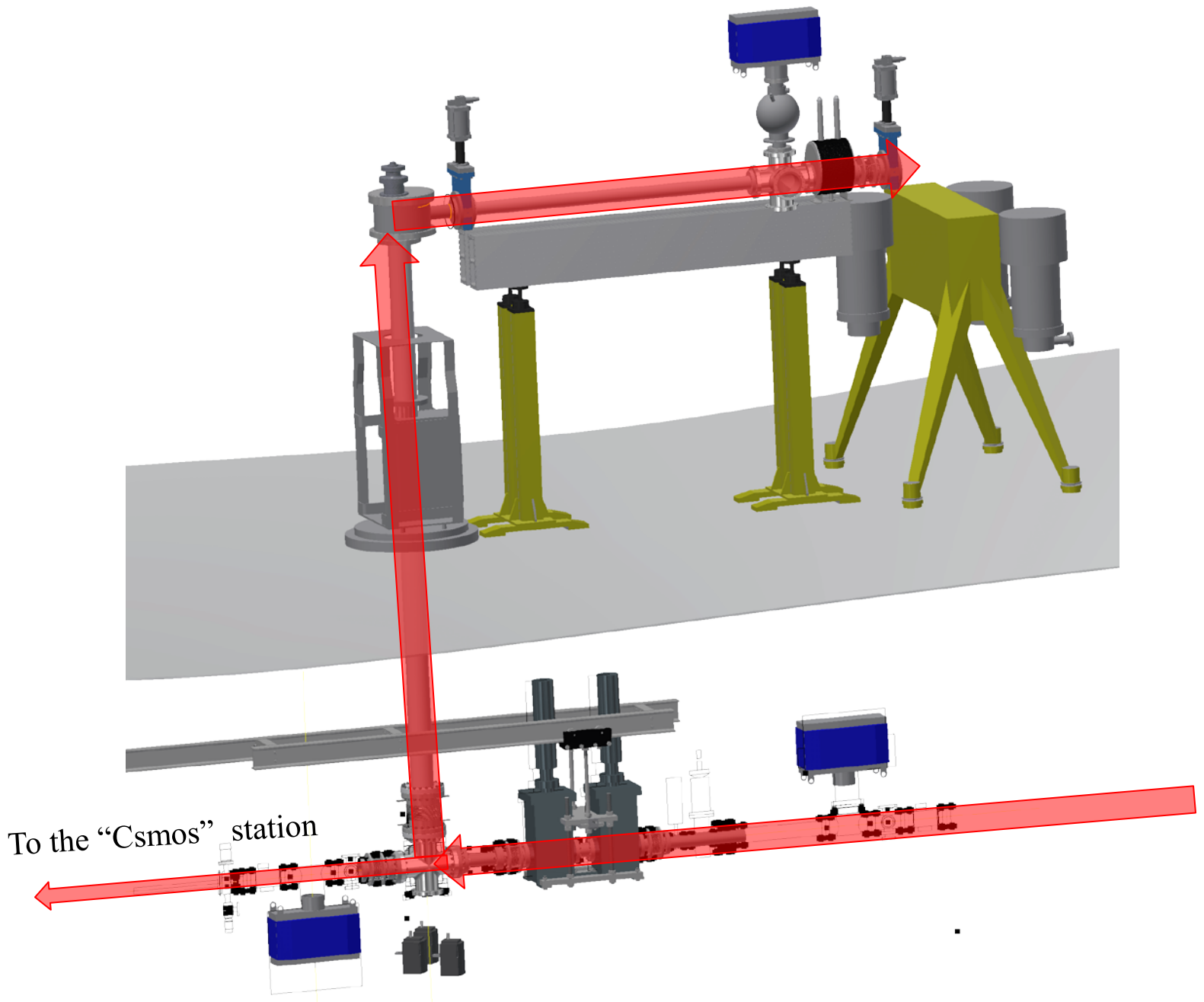
**SR station "Flame"**

**Cosmos experimental vacuum chamber**

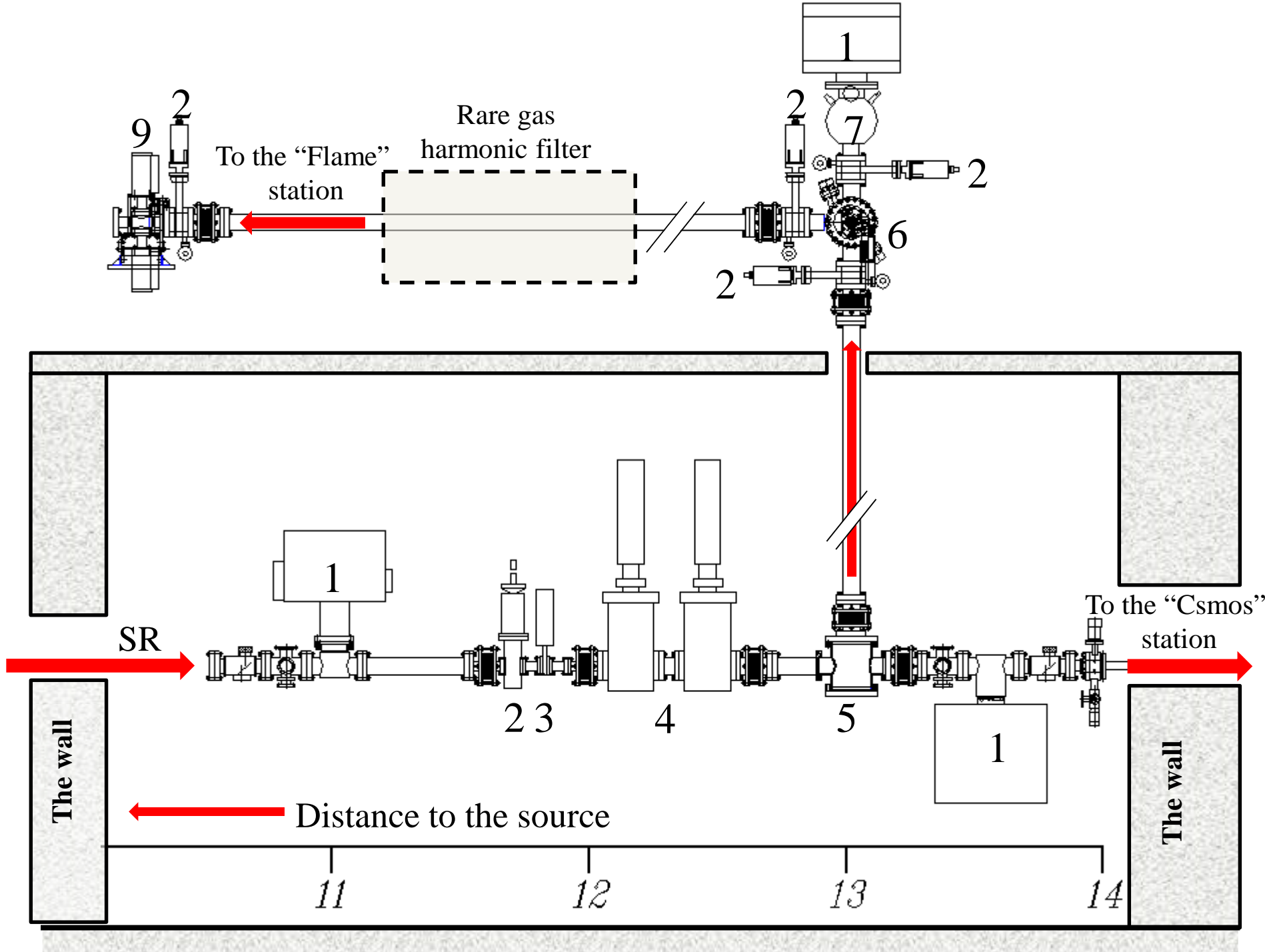


**SR**











# Project of new beamline “Flame”

## **Spherical mirror:**

R=12 m

Substrate – quartz

Coating – gold

Roughness – 15 Å

Aperture – 60x60 mm

## **Plane grating:**

Substrate – quartz

Coating – gold

Roughness – 15 Å

Number of grooves – 1500 per mm

Aperture – 30x40 mm

Rotation range: 4°-16.5°

Energy range: 5-25 eV (2000 eV - 500

eV)

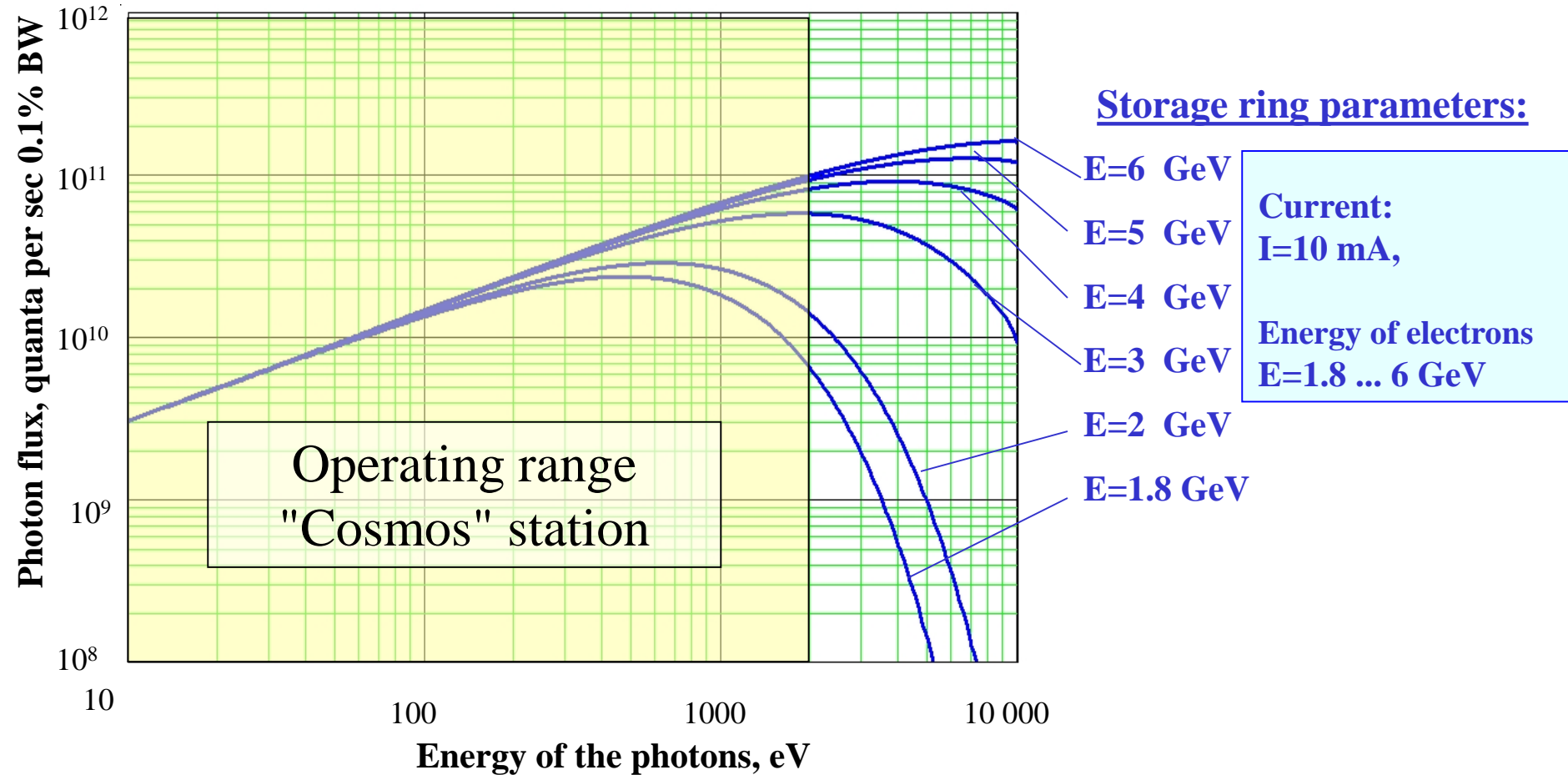
Spectral resolution:  $E/\Delta E=500-2000$



# Photon flux at the «Cosmos» station for different energy of electrons in the VEPP-4 storage ring.

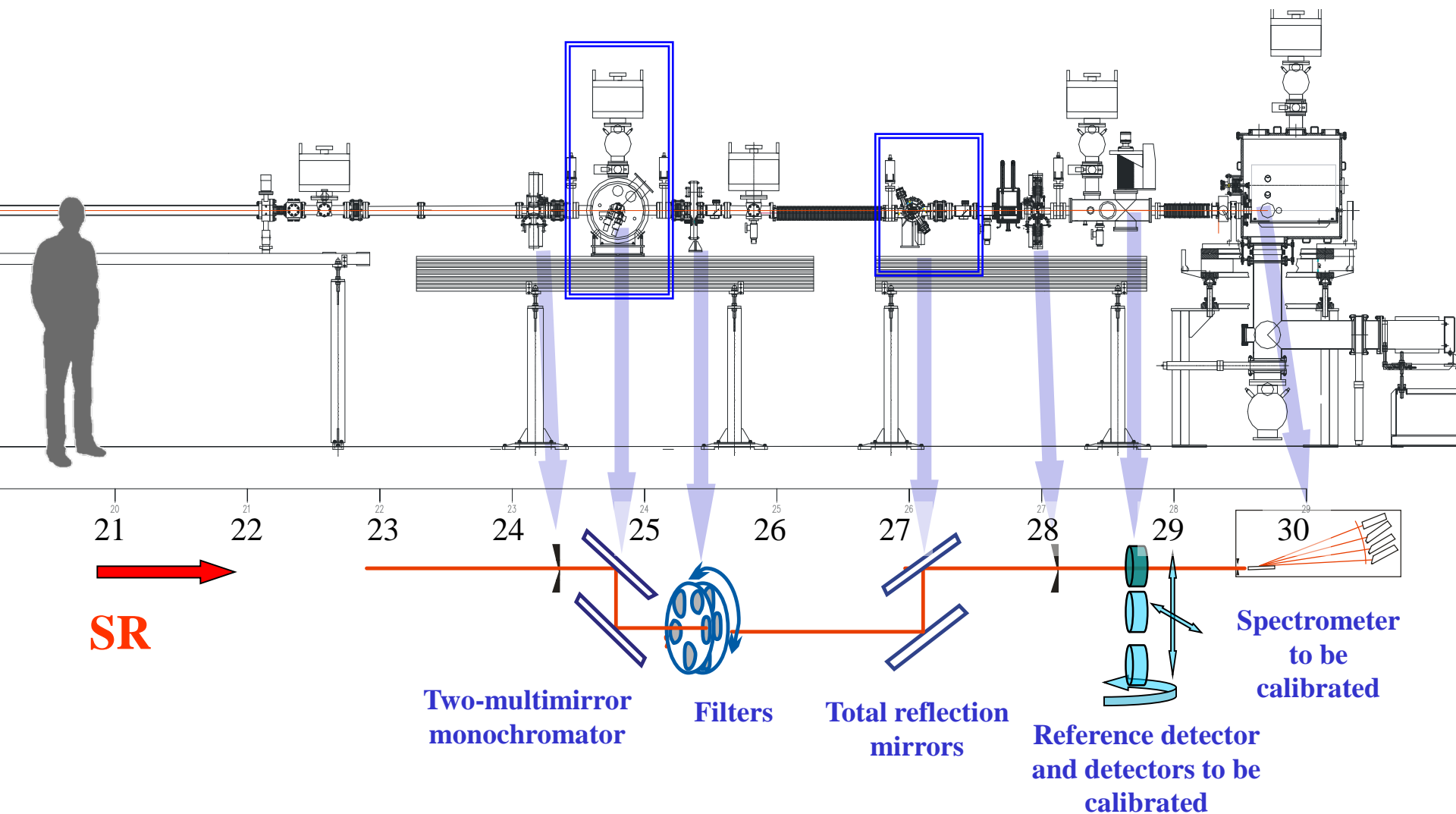
## Beamline parameters:

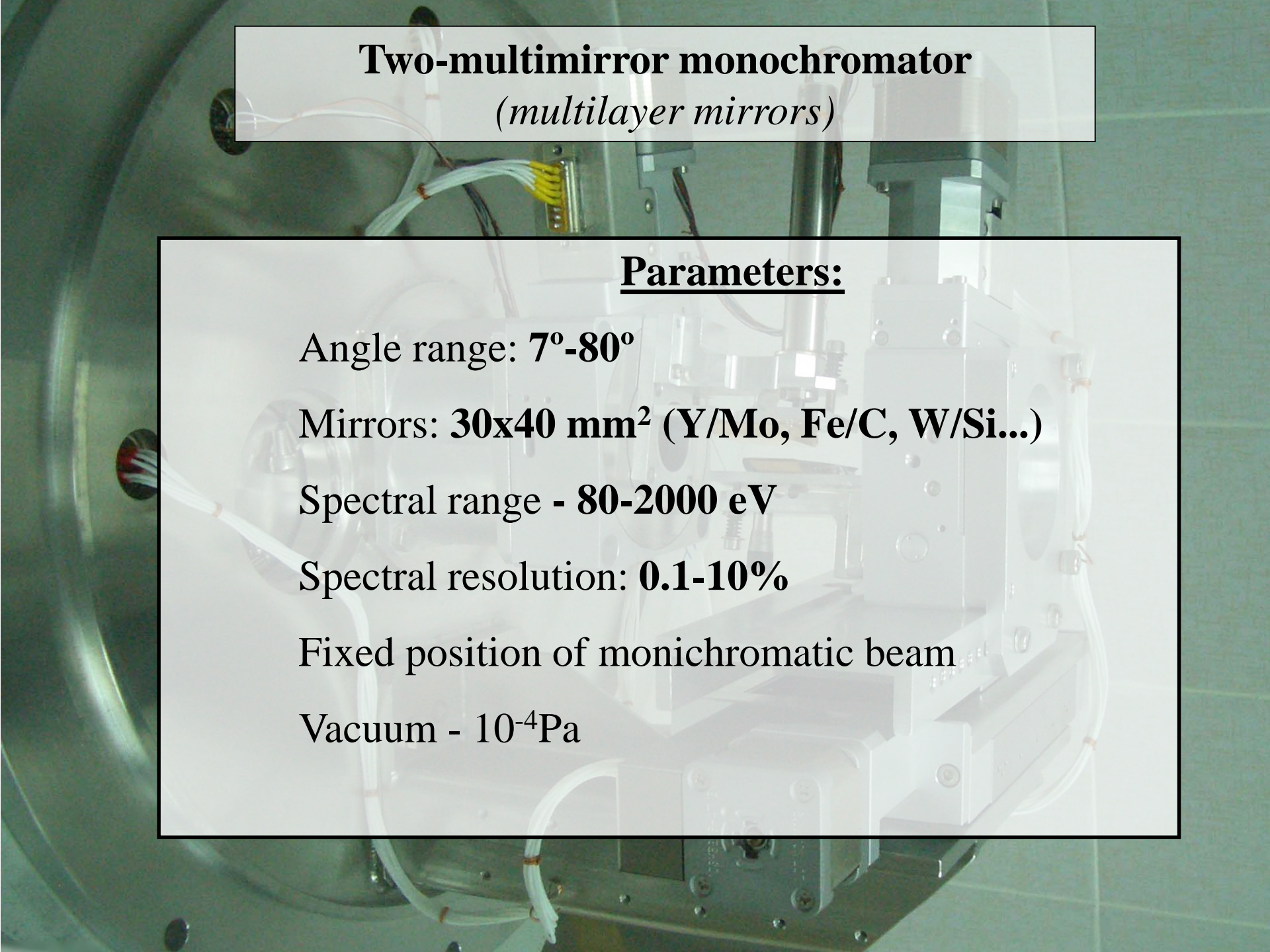
aperture - 5X5 mm, distance to the source - 30 m bandwidth  $\Delta E/E=10^{-3}$





# Layout and optical scheme of the COSMOS station





## **Two-multimirror monochromator** *(multilayer mirrors)*

### **Parameters:**

Angle range: **7°-80°**

Mirrors: **30x40 mm<sup>2</sup> (Y/Mo, Fe/C, W/Si...)**

Spectral range - **80-2000 eV**

Spectral resolution: **0.1-10%**

Fixed position of monichromatic beam

Vacuum - **10<sup>-4</sup>Pa**



# Two-multimirror monochromator (*multilayer mirrors*)

## Parameters:

Angle range: **7°-80°**

Mirrors: **30x40 mm<sup>2</sup>** (Y/Mo, Fe/C, W/Si...)

Crystals: **mica, KAP, CzAP...**

Spectral range - **80-2000 eV**

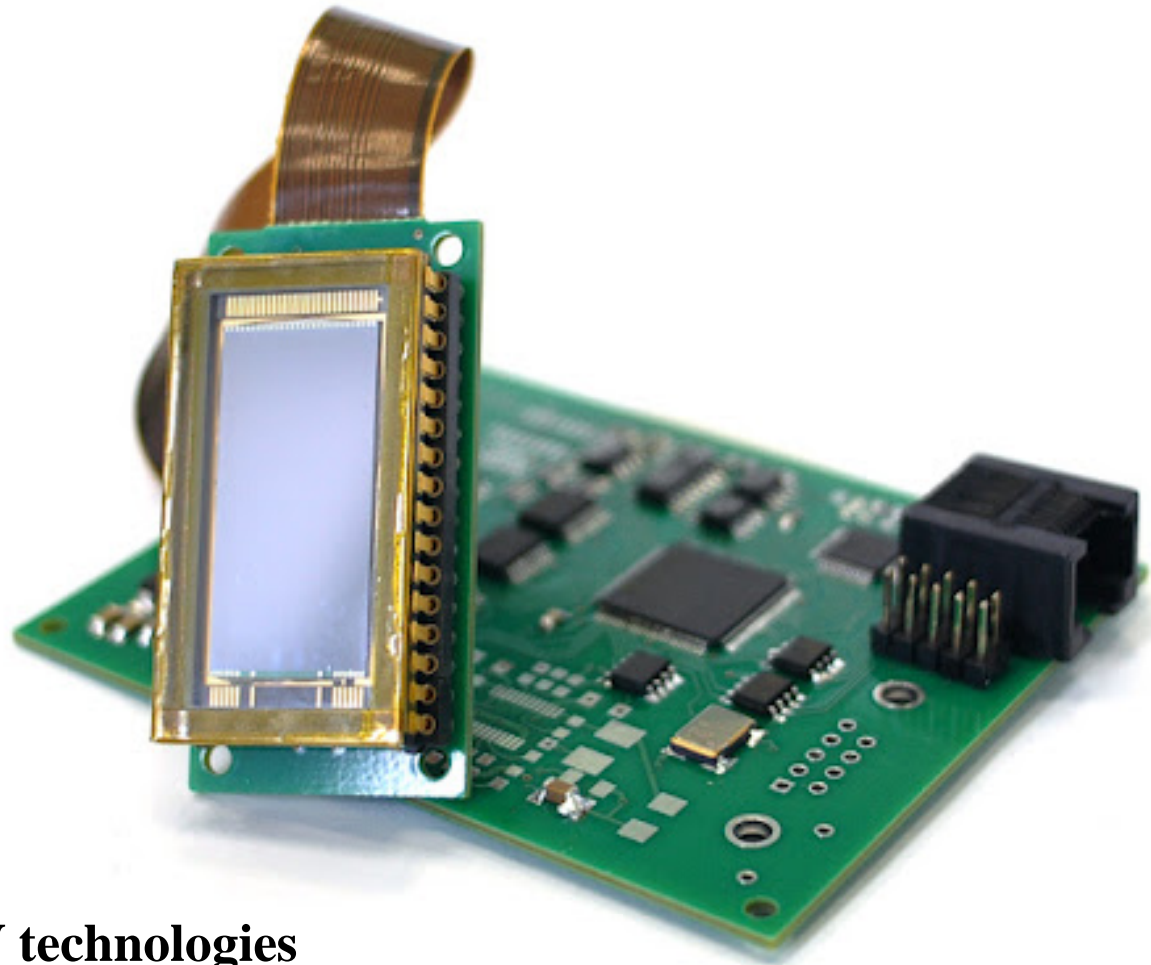
Spectral resolution: **0.1-10%**

Fixed position of monochromatic beam

Vacuum - **10<sup>-4</sup>Pa**

Acknowledgement to our colleagues from the Boreskov Institute of Catalysis SB RAS:  
*Evgeniy KOROTAEV, Lev MAZALOV, Mikhail SYROKVASHIN*

**Two-coordinate BI CCD –based detector**  
*(P.N. Lebedev Physical Institute of RAS, Moscow)*



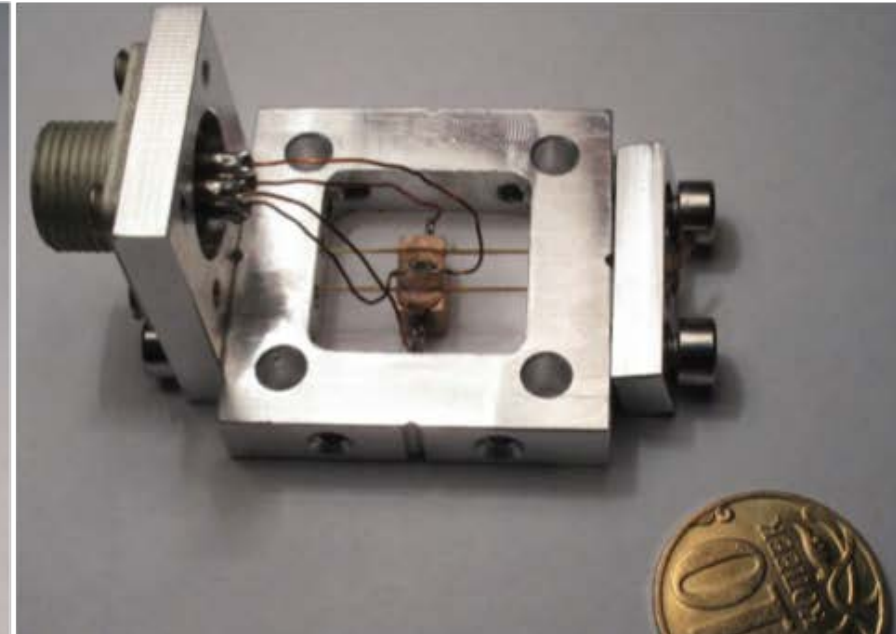
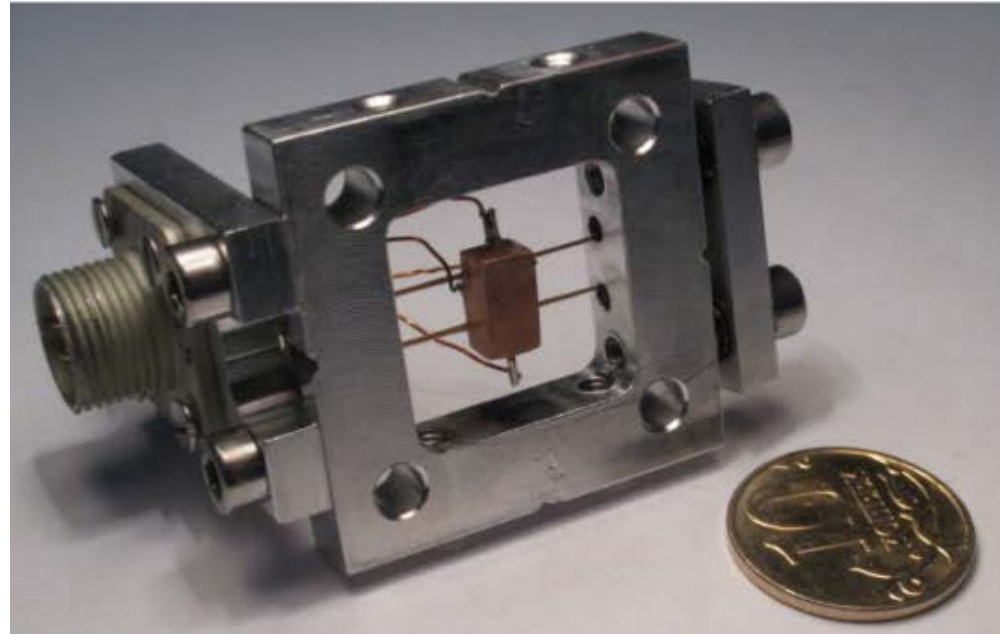
**E2V technologies**  
**Back Illuminated CCD Sensor**  
**(Gait Britain)**



# Calorimeter

*for the absolute measurement of the beam power of  $300\ \mu\text{W}$*

*Accuracy - 2-5%*



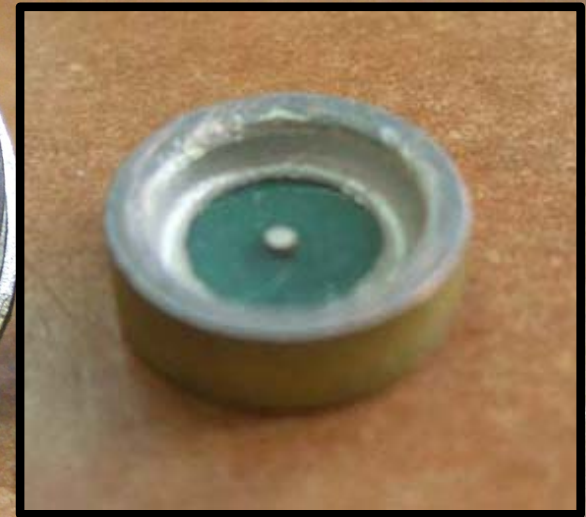
# Calibrated detectors



**SEM-6**



**p-n photodiode SPD**  
Ioffe Institute  
Saint Petersburg



**ETDRI-4**  
coaxial diamond detector  
Dukhov VNIIA, Moscow



**Solar UV radiation sensor**  
**VUSS-E**  
*Fedorov IAG, Moscow*



# **The main consumer characteristics of detectors**

- Spectral sensitivity
- Spatial sensitivity mapping
- Dark current
- Stability of characteristics
- Radiation resistance

# The main consumer characteristics of detectors

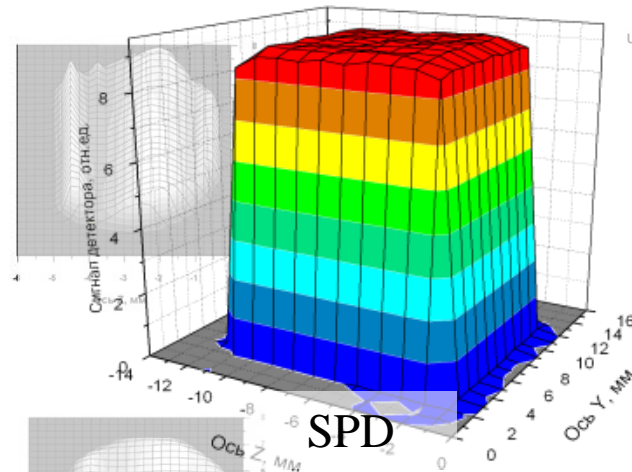
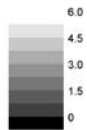
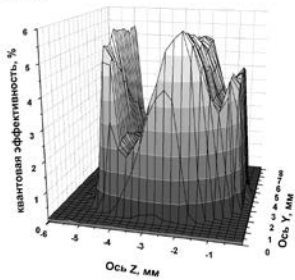
- **Spectral sensitivity**
  - *The method of the reference detector*
  - *Standard source method*
  - *Self-calibration method*
- Spatial sensitivity mapping
- Dark current
- Stability of characteristics
- Radiation resistance



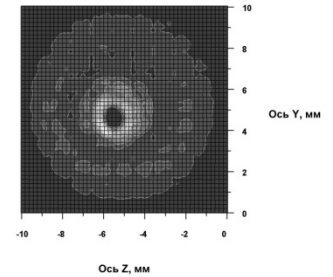
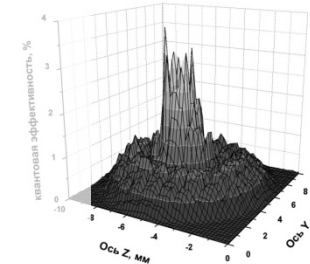
# The main consumer characteristics of detectors

- Spectral sensitivity
- **Spatial sensitivity mapping**
- Dark current
- Stability of characteristics
- Radiation resistance

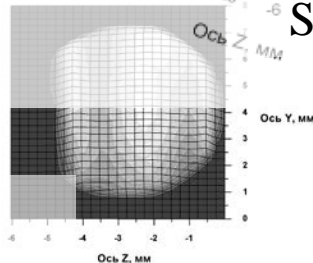
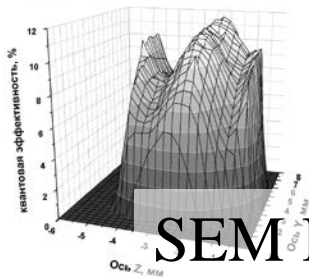
U = +2.5 кВ



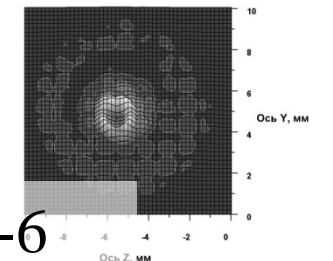
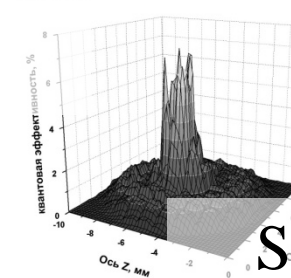
U = -2.0 кВ



U = +3.5 кВ



U = -2.4 кВ



SEM KSP

SEM-6

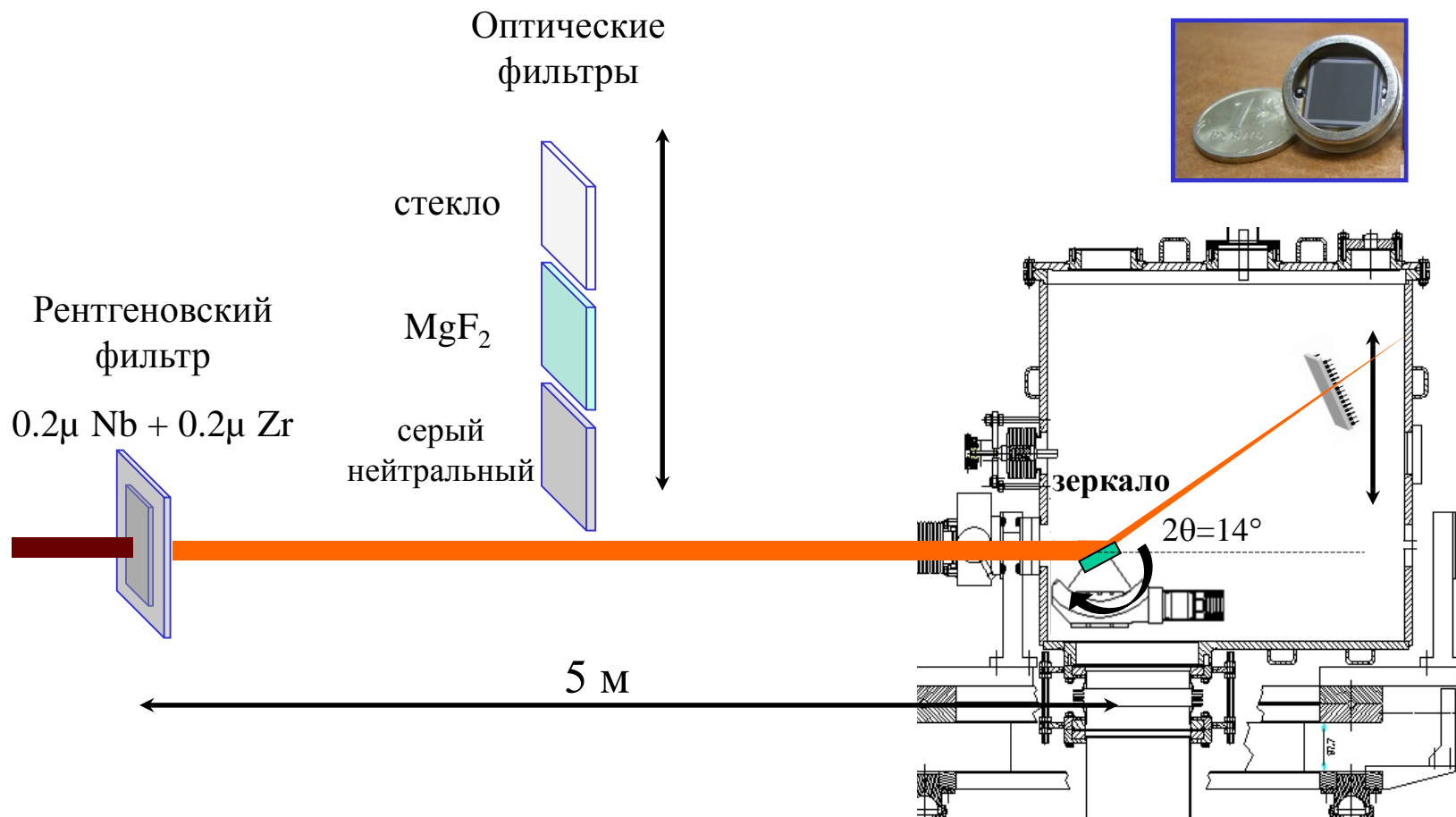
# The main consumer characteristics of detectors

- Spectral sensitivity
- Spatial sensitivity mapping
- Dark current
- Stability of characteristics
- **Radiation resistance**



# Облучение фотодиода:

## Схема фокусировки и фильтрации

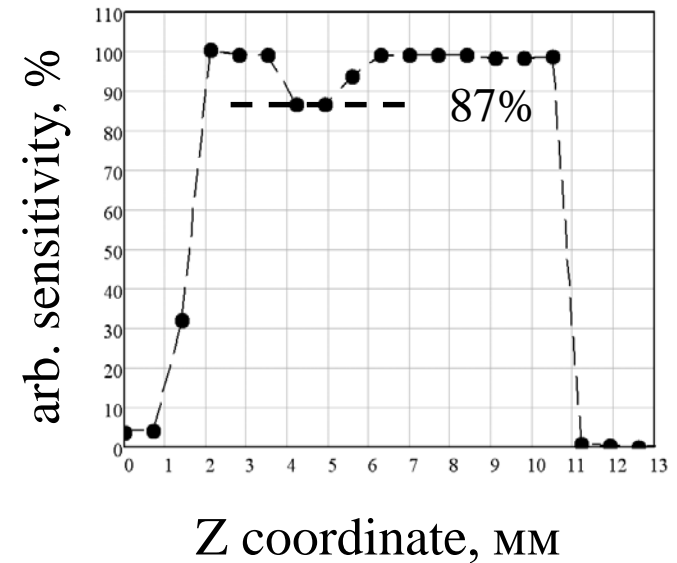
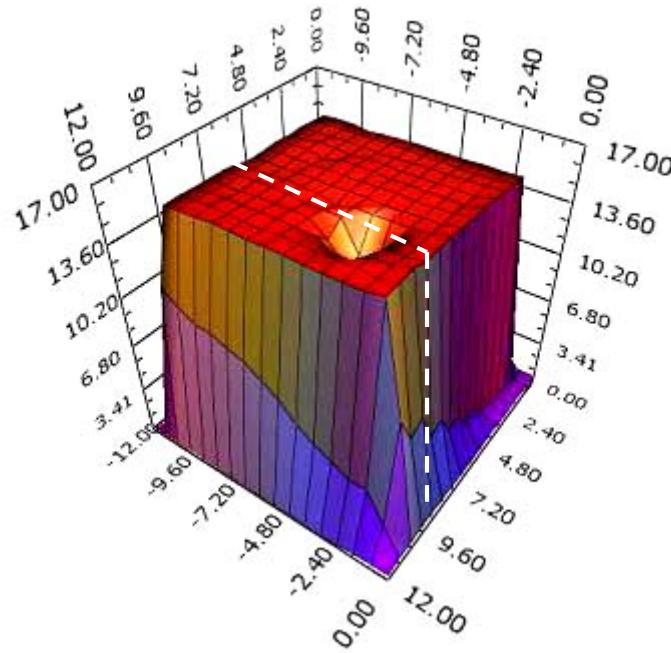
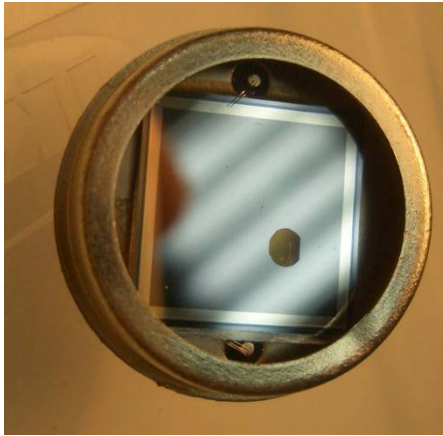


Фокусировка сферическим зеркалом  $R=10$  м,  $\theta=7^\circ$ . Выигрыш - в 5 раз.

Одновременно работает как зеркало ПВО

# Radiation hardness of the SPD photodiode:

*appearance and sensitivity map after irradiation with 1.8 MGy dose*

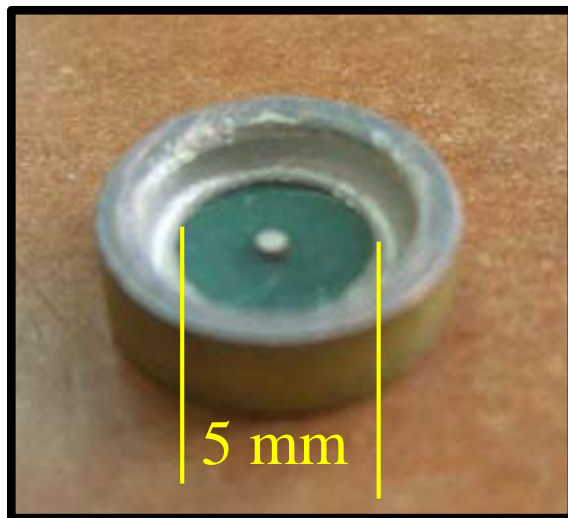


Dose: 1.8 MGy ( $123 \text{ J}/\text{sm}^2$ ) & 80-160 eV

Surface scan was provided at the photon energy 100 eV. The magnitude degradation - 13% and does not vary substantially within the spectral range 97-130 eV.



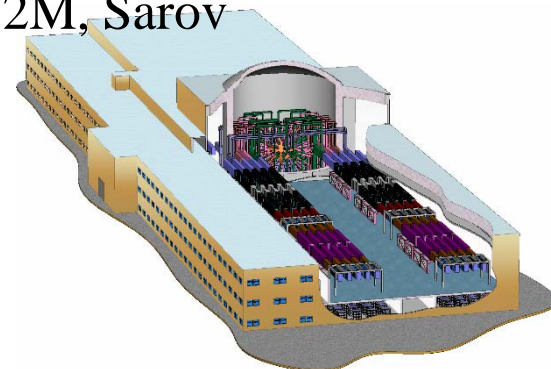
# Preliminary calibration of the sensitivity of the diamond detector ETDRI-4



Developer L.M. Dukhov VNIIA, Moscow

Coaxial diamond windowless detector

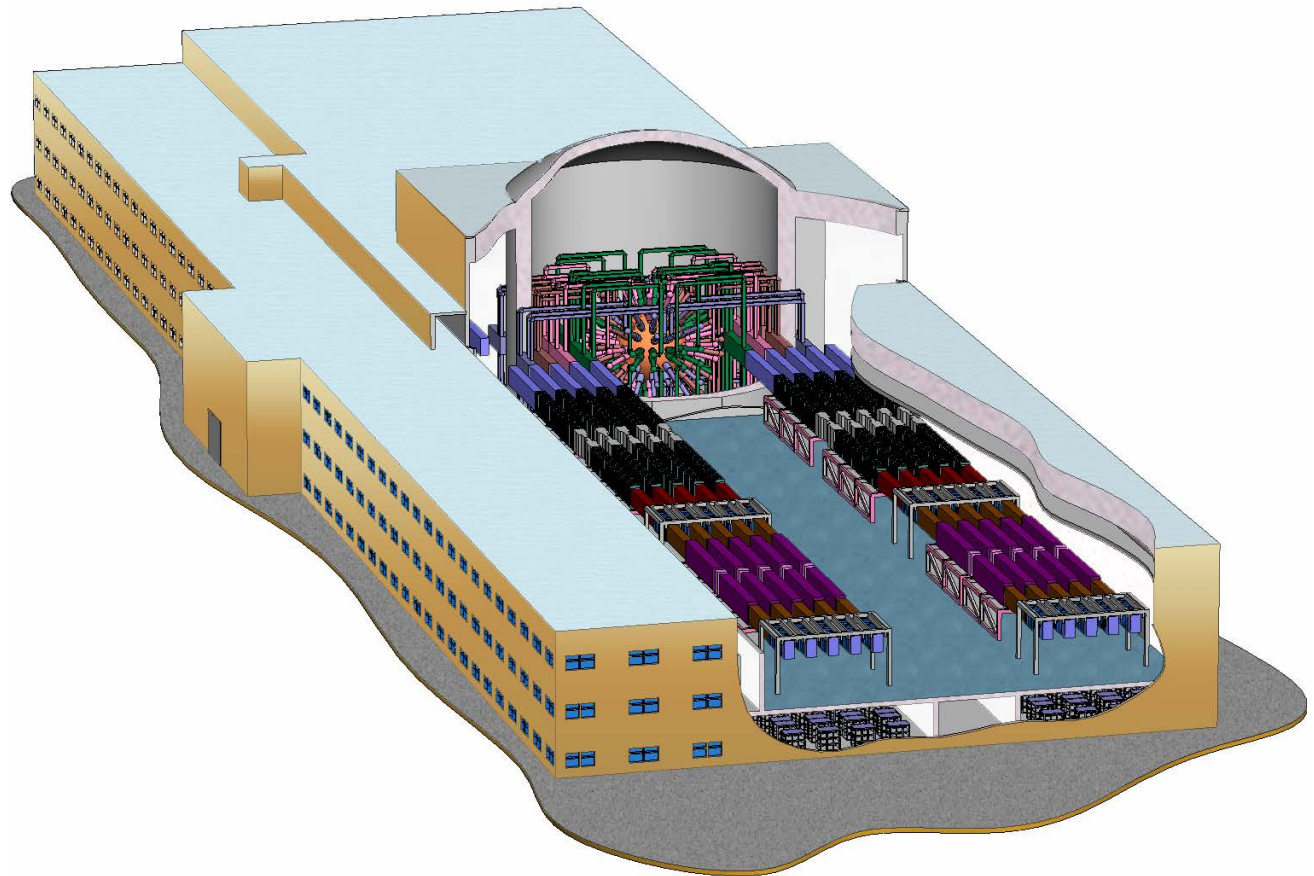
It is supposed to use at the megajoule laser facility UFL-2M, Sarov



# Megajoule laser facility UFL-2M (Sarov)

*for the study laser thermonuclear fusion*

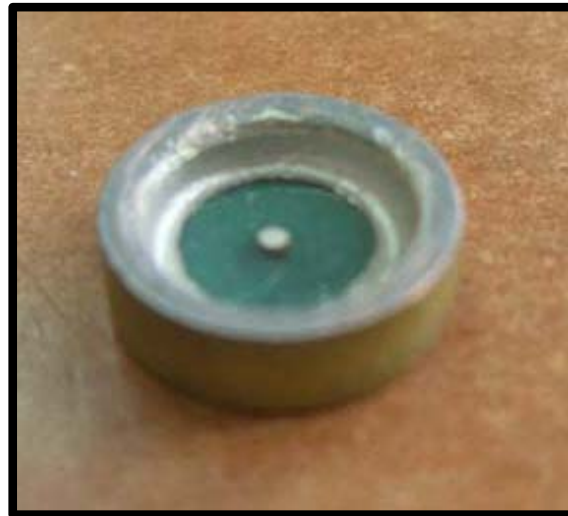
- 192 laser beam
- 4.6 MJ &  $\lambda=1053$  nm
- Impulse profiled with a duration of 5-10 ns
- Power - 500 TW





## Features of the detector:

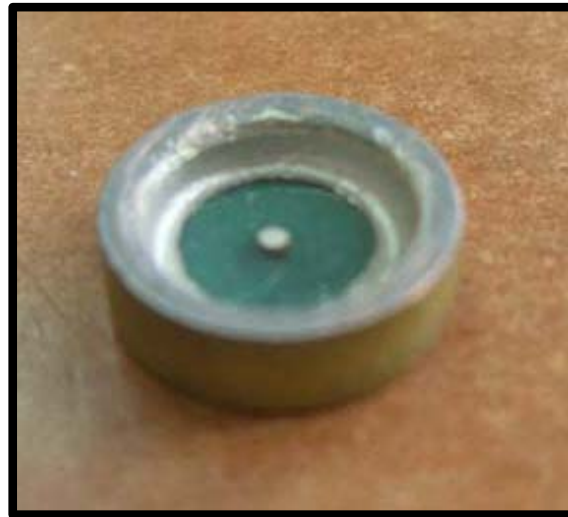
- High radiation resistance
- Solar blind
- The flat spectral response
- High time resolution (100-150 ps)
- Low sensitivity



ETDRI-4

## Features of the detector:

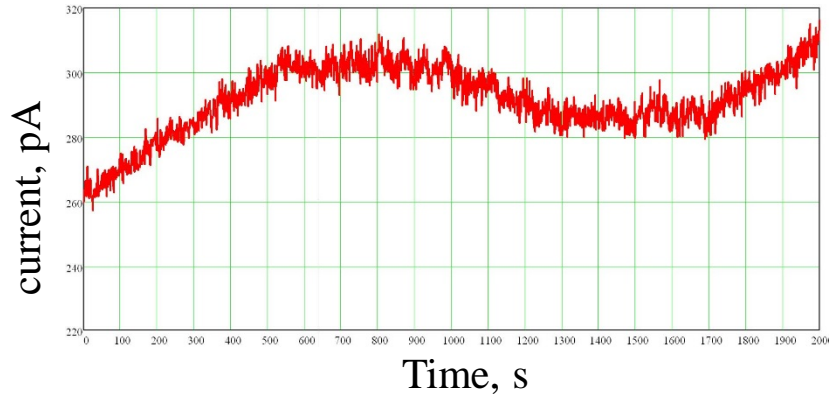
- High radiation resistance
- Solar blind
- The flat spectral response
- High time resolution (fractions of a nanosecond)
- **Low sensitivity**



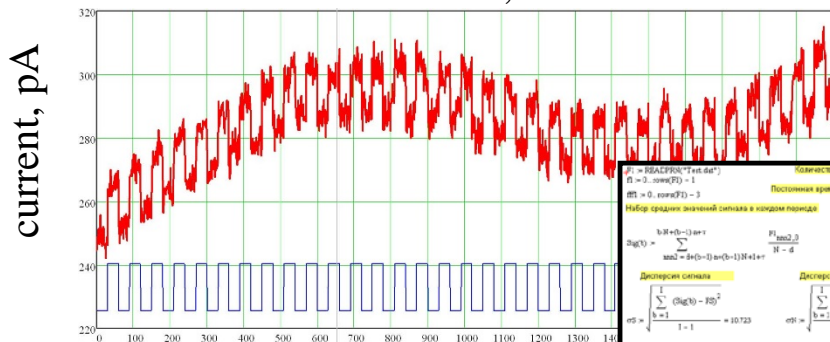
ETDRI-4

**A low signal to noise ratio**

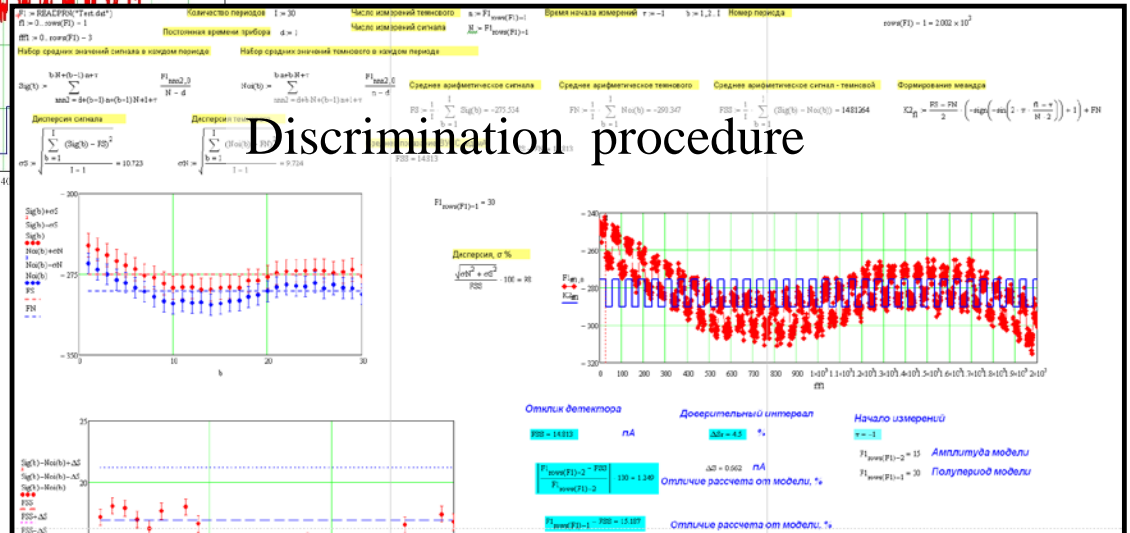
# Testing signal-noise discrimination procedure for the ETDRI-4 (computer simulation)



dark current  
(real measurements)



dark current  
+ meander



accuracy of recovery of the  
meander amplitude :  
 $\sigma = 2\%$



# Synchrotron radiation source as primary standard of soft X-ray radiation

$$\Psi = \Psi (E_{phot}, \Delta E_{phot}/E_{phot}, T_{beam}, j_{beam}, \Sigma_z, B, A, L, \varphi)$$

## Storage ring parameters:

$E_{phot}$  - photon energy,

$\Delta E_{phot}/E_{phot}$  - spectral range,

$T_{beam}$  - energy of storage ring,

$j_{beam}$  - beam current,

$B$  - value of magnetic field induction in the emission point

$\Sigma_z$  - vertical emittance,

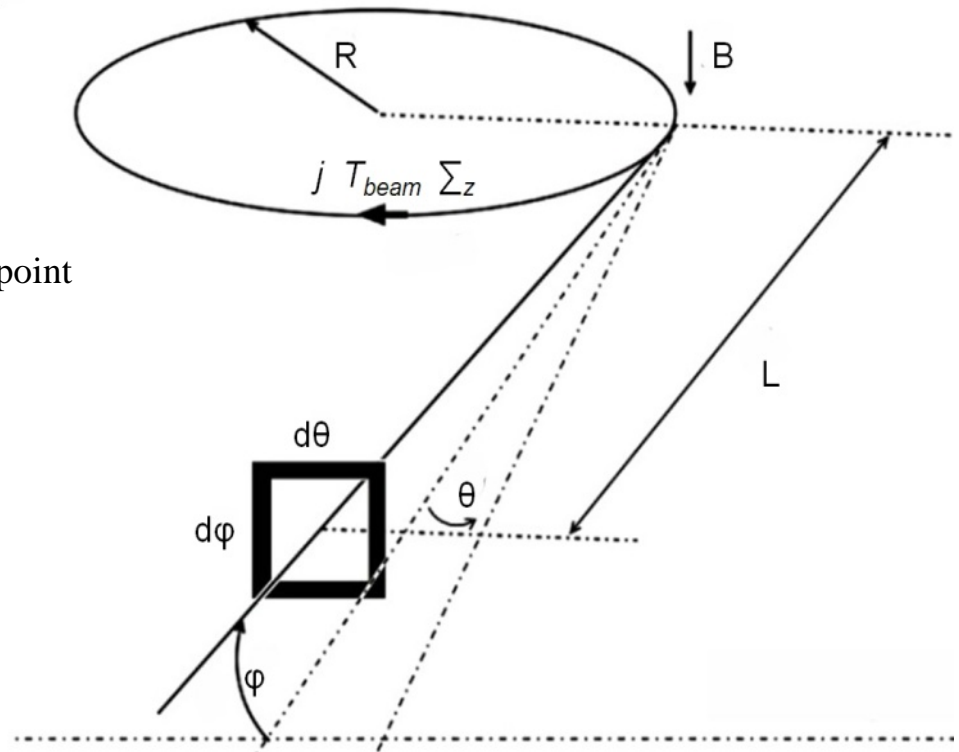
$$\Sigma_z = (\sigma_z^2 + d^2 \sigma_z'^2)^{1/2}.$$

## The geometrical parameters:

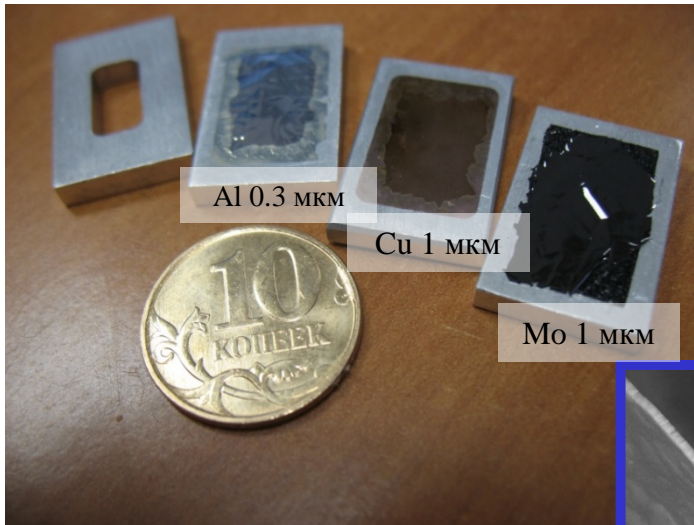
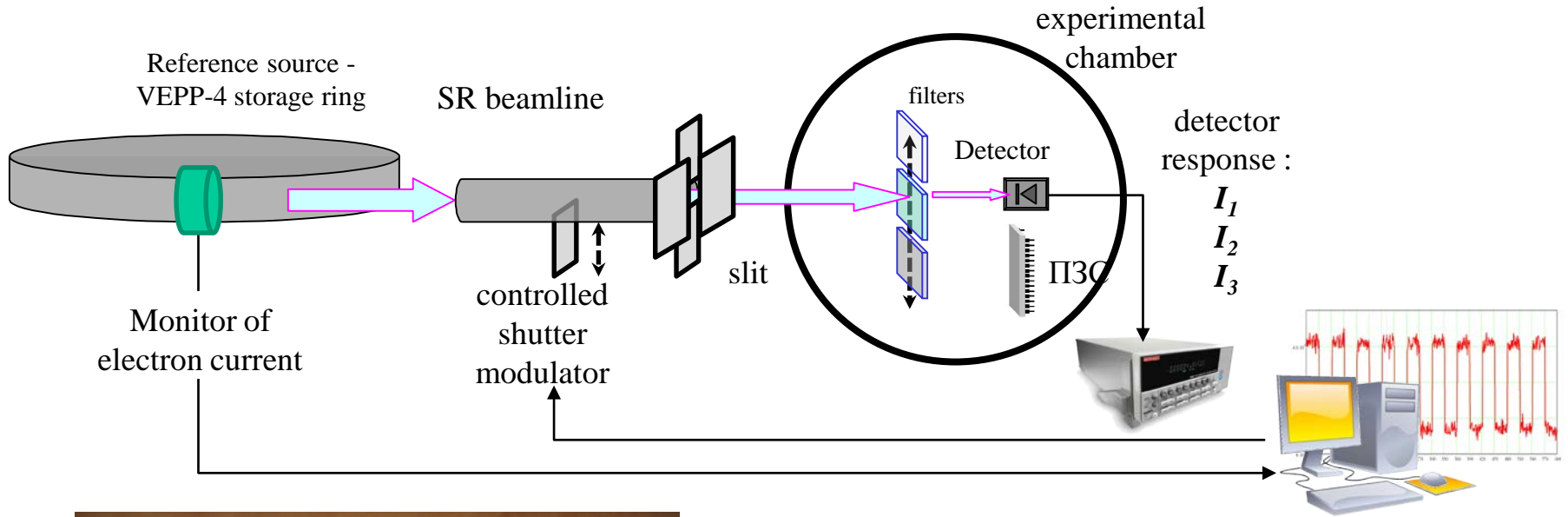
$A = A(d\varphi, d\theta)$  - receiving aperture settings

$L$  - distance to the emission point

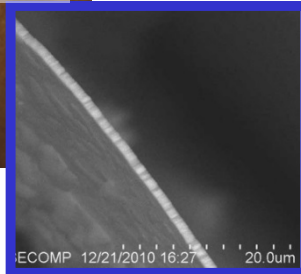
$\varphi$  - vertical angle from the median plane



# Experimental setup

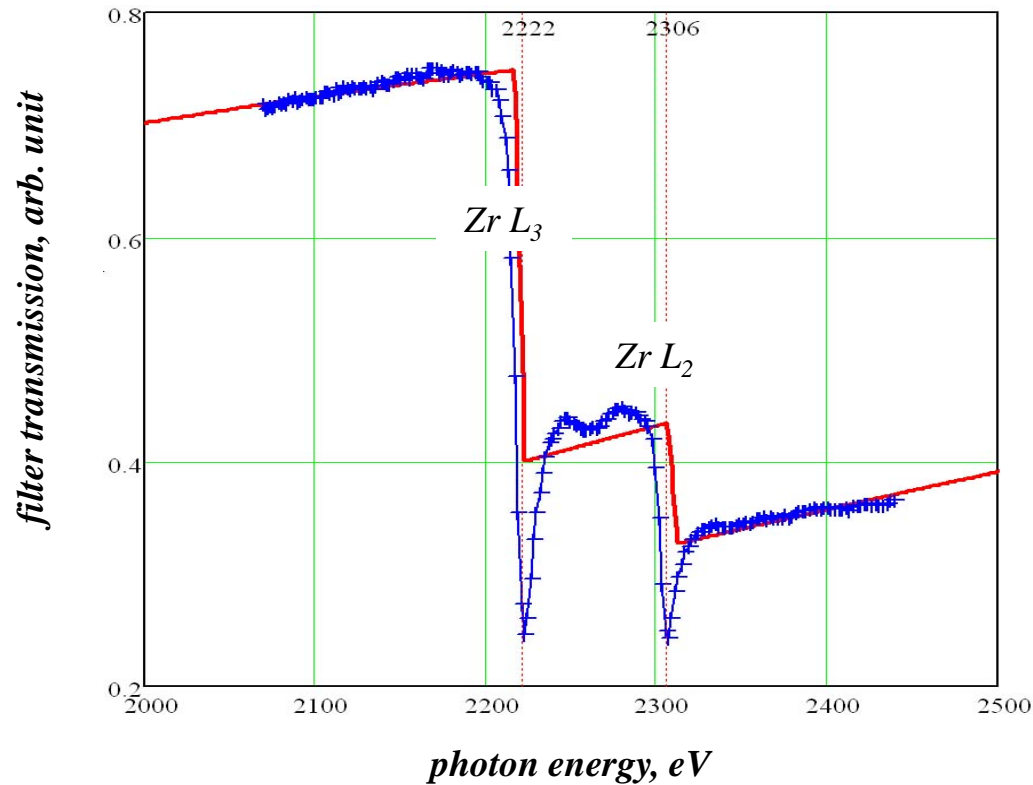


Filters



# Certification of the selective filters

*measurement of the transmission near the K or L-edges of the filter material*



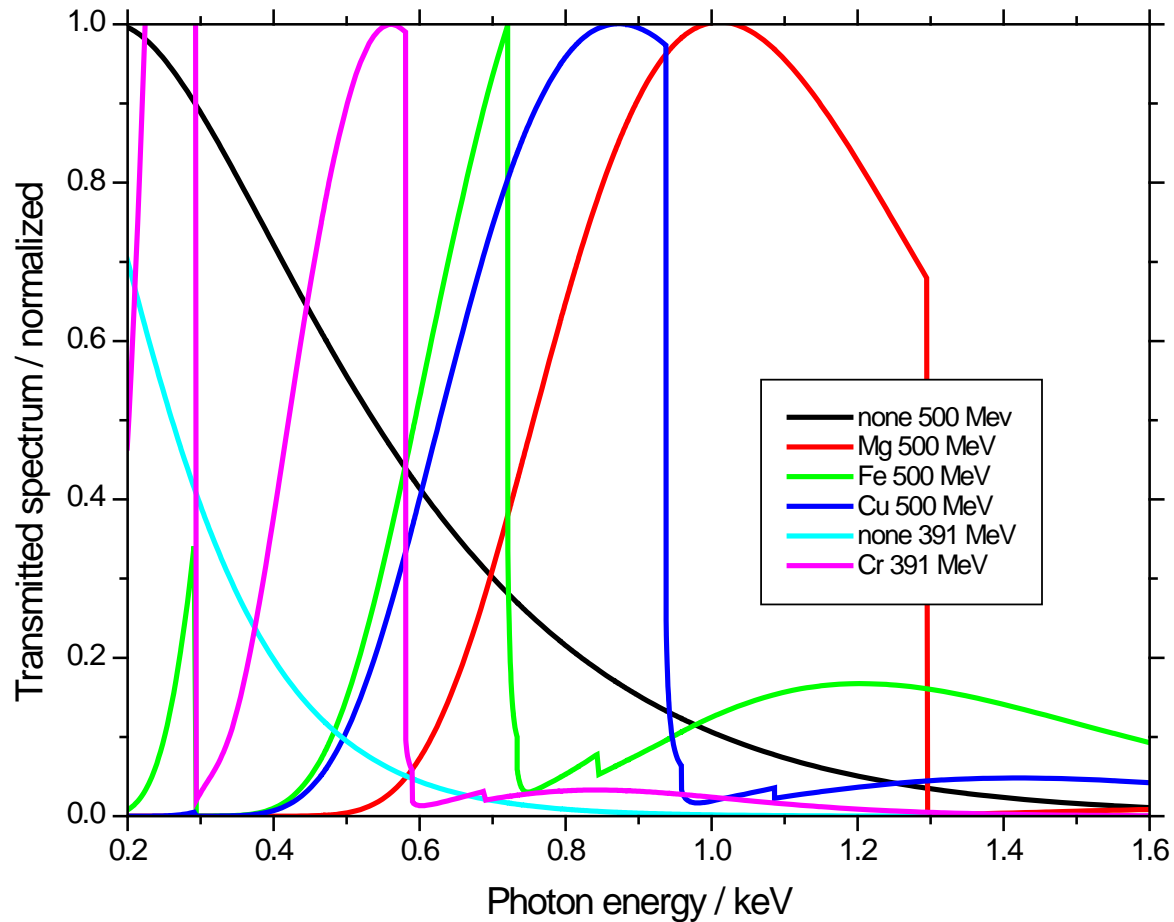
Measurement transmission of the Zr filter (monochromator crystals - mica).  
Comparison with the CXRO data base (red graph) gives the thickness of the filter - 0.54  $\mu\text{m}$

[http://henke.lbl.gov/optical\\_constants/](http://henke.lbl.gov/optical_constants/)



# The estimated power spectral density of the SR after the filters

$$P(E) = f(E) \psi(E) dE/E$$



Filters are polymer film with metal coating or the thin metal film  
Fe, Cu, Mg, Cr, Al etc.  
the thickness of the filter should be certified

## Solution of a system of integral equations

$$I_i = \int_0^{\infty} P_i(E) \cdot S(E) dE + \xi_i$$

$P_i$  - spectral power distribution of the SR after i-th filter

$S(E)$  – spectral sensitivity of the detector

The system is solved by the limited optimization of Boxing (a type of flexible polyhedron method).

To stabilize the solution we use parametric definition of the functions  $S(E)$ .

$$S(E) = \frac{e}{w} \cdot k \cdot \exp[-\mu_c(E)h_c] \cdot \exp[-\mu_d(E)h_d] \cdot \left(1 - \exp[-\mu_s(E)h_s]\right)$$

$h_c$   $h_d$   $h_s$  - variable parameters: the deposition thickness of the dead and the active layers of the detector

$k$  - charge collection efficiency of the detector

# The appearance of the interface window for solving the system of equations written by our colleagues from Polzunov Altai State Technical University, Barnaul

The image displays a software interface for solving a system of equations, likely related to X-ray semiconductor detector calibration. The interface is divided into several sections:

- Configuration Panels:** On the left, there are four panels labeled "Файл № 1" through "Файл № 4", each containing fields for "Путь к файлу" (File path), "Масса" (Mass), and "Толщина" (Thickness).
- Паспортные значения (Passport values):** A central panel showing parameters  $k$ ,  $hd$  нМ,  $hc$  нМ, and  $hs$  нМ, with input fields and checkboxes for "не изменять" (do not change).
- График (Graph):** On the right, a graph titled "Поглощение" (Absorption) showing "Поглощение" (Absorption) on the y-axis and "Число фотоэлектронов" (Number of photoelectrons) on the x-axis. The graph displays several peaks, with the highest peak at approximately 1000 photoelectrons.
- Calibration Report:** A central report window titled "Calibration Report" with the subtitle "Absolute calibration of X-ray semiconductor detectors against synchrotron radiation". It includes a diagram of a detector and a table of calibration results.
- Filters:** A table at the bottom right showing a list of filters with their respective parameters and detector current values.

**Calibration Results Table:**

Parameter	Value	Parameter	Value
$km$	0.50000001	$hcm$	0.2182254287
$hdm$	0.2076827846	$hsm$	65.308546740

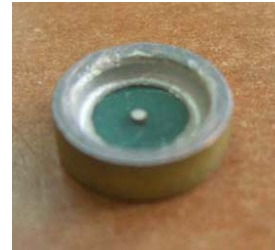
**Filters Table:**

Filter Name	Count of Filters
the mass thickness of base layer	1
path of base layer's data file	1.1
path of coating's data file	C:\Program Files\Detector\example\filters\11mkm_Co.txt
the mass thickness of coating	0.17
the detector current	2013
the mass thickness of base layer	1
path of base layer's data file	1.1
path of coating's data file	C:\Program Files\Detector\example\filters\11mkm_Ni.txt
the mass thickness of coating	0.29
the detector current	1.3656
the mass thickness of base layer	1
path of base layer's data file	1.65
path of coating's data file	C:\Program Files\Detector\example\filters\11mkm_Cu.txt
the mass thickness of coating	0.5
the detector current	0.6656
the mass thickness of base layer	1
path of base layer's data file	2.4
path of coating's data file	C:\Program Files\Detector\example\filters\11mkm_Mg.txt
the mass thickness of coating	6.49
the detector current	0.614



# Preliminary sensitivity calibration result & 1000 eV :

ETDRI-4 -  $2.3 \cdot 10^{-5} \text{ A/W}$



For comparison:

X-ray vacuum diode -  $1.7 \cdot 10^{-5} \text{ A/W}$



Silicon photodiode SPD -  $0.27 \text{ A/W}$

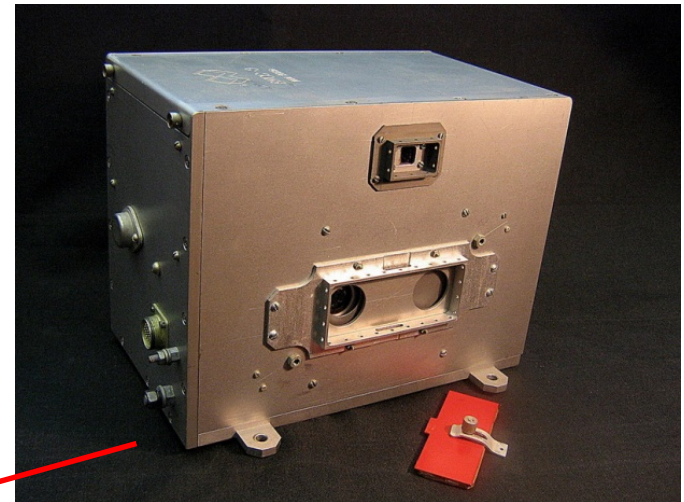


# Calibration of the Solar UV radiation sensor VUSS-E for the geostationary satellite "Electro-L №3"

*Customer - Fedorov IAG, Moscow*

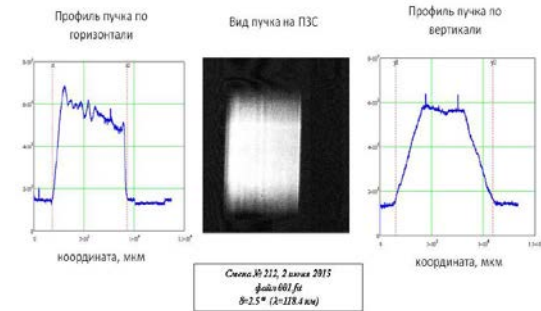
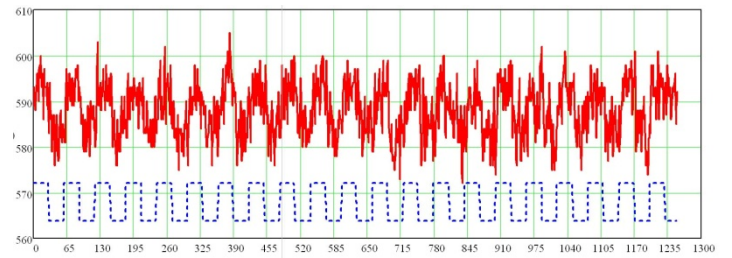
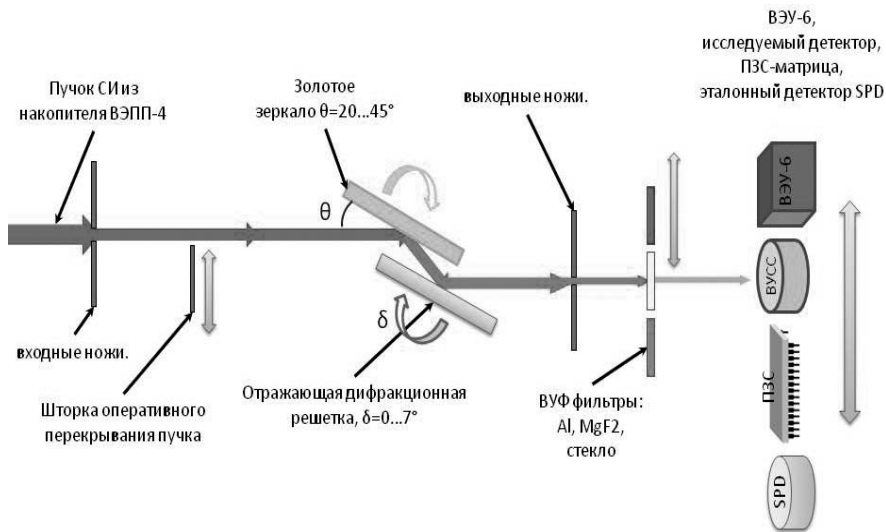
Fluxmeter to measure the intensity  
at 121.6 nm (H Lyman alpha-line)

Expected launch - 2017

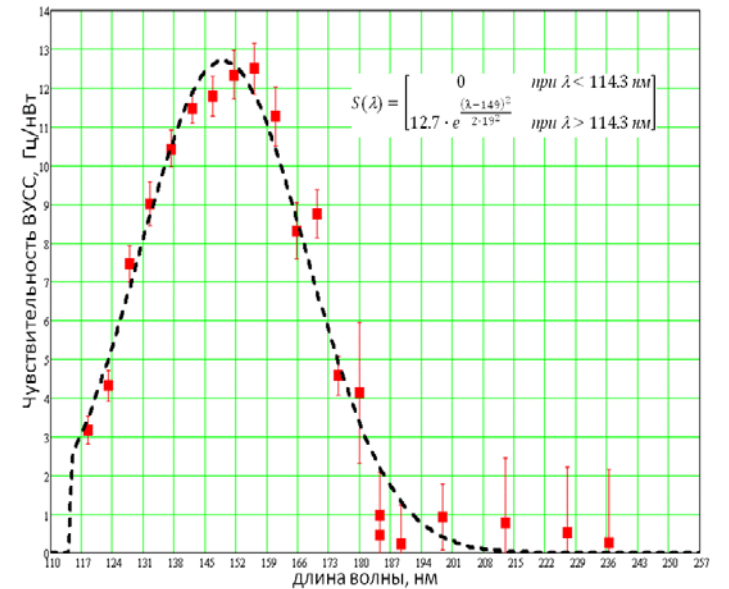
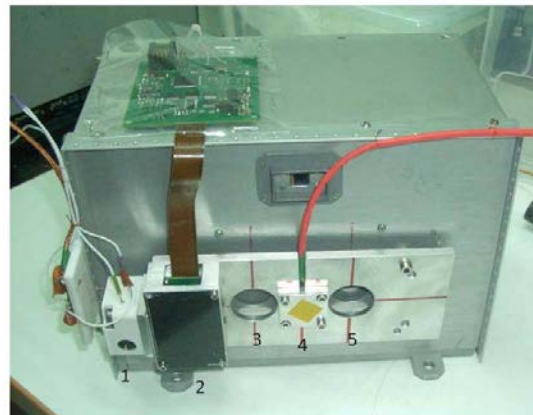


based on the PMT-154

# Method of the reference detector



Calibration certificate Номер сертификата Certificate number	1-2015	Страница Page	1 из 2 of 2
Федеральное государственное бюджетное учреждение науки Институт ядерной физики им. Г.И. Будкера Сибирского отделения Российской академии наук ИЯФ СО РАН *Nuclear Institute of Nuclear Physics Siberian Federal University Academy of Sciences NSP SB RAS		Федеральное государственное учреждение «Сибирский государственный Оптический Трудовой Красноярецкий научно-исследовательский институт метрологии ФГУП «СИНММ» Federal Scientific Research Institute of Metrology FSUE «SINMM»	
<b>Сертификат калибровки</b> Calibration certificate			
Номер сертификата Certificate number	1-2015	Дата калибровки Date when calibrated	10.07.2015
Страница Page	1	из of	2
Объект калибровки Item calibrated	Измеритель ультрафиолетового излучения Система типа ВУСС детекторизованная аппаратурой комплекса ГТК		
Заказчик Customer	Заказчик: ФГУП «НИИ» 129128, г. Москва, ул. Ростокинская, д.9 НИИ 771402312		
Метод калибровки Method of calibration	Косвенная определение чувствительности при измерении мощности излучения с помощью эталонного детектора		
Калибровка выполнена с погрешностью Calibration is performed by using	Детекторы SPD-100 UV, микроаналитики Кейблы 2502, станции спектрометрического излучения «Кельвин», «Атомикон» ВЭП-4 (ИЯФ СО РАН)		
Условия калибровки Calibration conditions	Температура 25°C, отклонение 60%, атм.давление 99,8 мПа		
Утверждающая подпись Authorized signature	Директор: Г.В. Шувалов Заместитель: Е.К. Левченко		





# Conclusions

At the station Cosmos worked out a number of procedures for certification of basic consumer qualities of different kinds of detectors :

- Spectral sensitivity (calibration accuracy 1-10%)
  - *method of the reference detector*
  - *standard source method*
  - *self-calibration method*
- Spatial sensitivity mapping
- Dark current
- Stability of characteristics
- Radiation resistance



 **XVI МЕЖДУНАРОДНАЯ КОНФЕРЕНЦИЯ ПО  
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10 - 18 июля 2006 г.





**Спасибо за внимание**



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